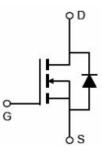


#### Main Product Characteristics:

V <sub>DSS</sub>	60V
R <sub>DS</sub> (on)	25mΩ(typ.)
Ι <sub>D</sub>	20A







TO-252 (DPAK)

Marking and Pin Assignments

Schematic Diagram

#### **Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- AEC-Q101 qualified



#### **Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

#### **Absolute Max Rating:**

Symbol	Symbol Parameter			
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V①	20		
I <sub>DM</sub>	Pulsed Drain Current②	80	A	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation3	23	W	
V <sub>DS</sub>	Drain-Source Voltage	60	V	
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy @ L=0.5mH	34	mJ	
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C	



### **Thermal Resistance**

Symbol	Characteristics	Тур.	Max.	Units
Rejc	Junction-to-case③	_	5.4	°C <b>/W</b>

#### **Electrical Characteristics** $@T_A=25$ °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	60	_		V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance		25	35	mΩ	V <sub>GS</sub> =10V,I <sub>D</sub> =4.5A
			31	45		V <sub>GS</sub> =4.5V,I <sub>D</sub> =3A
$V_{GS(th)}$	Gate threshold voltage	1	_	3	V	$V_{DS}$ = $V_{GS}$ , $I_D$ =250 $\mu$ A
I <sub>DSS</sub>	Drain-to-Source leakage current	_	_	1	μA	V <sub>DS</sub> =60V,V <sub>GS</sub> = 0V
	Cata to Source forward lookage	_	_	100	nA	V <sub>GS</sub> =20V
I <sub>GSS</sub>	Gate-to-Source forward leakage		_	-100		V <sub>GS</sub> = -20V
Qg	Total gate charge	_	20			I <sub>D</sub> = 10A,
Q <sub>gs</sub>	Gate-to-Source charge	_	3.5		nC	V <sub>DS</sub> =30V,
Q <sub>gd</sub>	Gate-to-Drain("Miller") charge		5	_		V <sub>GS</sub> = 10V
t <sub>d(on)</sub>	Turn-on delay time		7.6	_		N/ 40X/ X/ 20X/
tr	Rise time		22	_		$V_{GS}$ =10V, $V_{DS}$ =30V, $R_{GEN}$ =3 $\Omega$ $I_D$ = 20A
t <sub>d(off)</sub>	Turn-Off delay time		21	_	ns -	
t <sub>f</sub>	Fall time		3	_		$I_D = 20A$
Ciss	Input capacitance	_	818	_		V <sub>GS</sub> = 0V
Coss	Output capacitance	_	45	_	pF	V <sub>DS</sub> = 50V
C <sub>rss</sub>	Reverse transfer capacitance	_	36	_		f = 1MHz

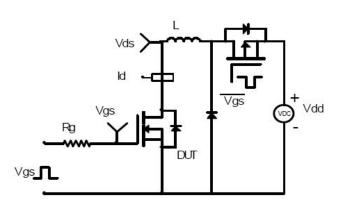
## **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current	—	—	20	А	MOSFET symbol	
	(Body Diode)					showing the	
	Pulsed Source Current			80	A	integral reverse 🚽 🕂	
I <sub>SM</sub>	(Body Diode)		_	80	A	p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.2	V	I <sub>S</sub> =1.7A, V <sub>GS</sub> =0V	
trr	Reverse Recovery Time		30	_	ns	L-204 di/dt-1004/up	
Qrr	Reverse Recovery Charge	—	40	_	nC	Is=20A,di/dt=100A/us	

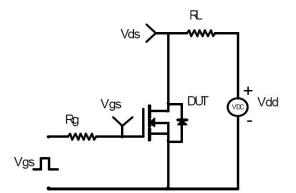


### **Test Circuits and Waveforms**

EAS Test Circuit:

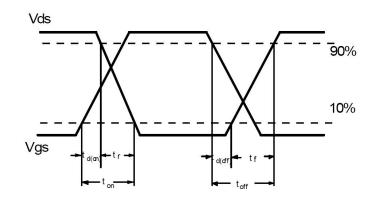


Switching Time Test Circuit:



Switching Waveforms:

Gate Charge Test Circuit:



#### Notes:

①Calculated continuous current based on maximum allowable junction temperature.

- ② Repetitive rating; pulse width limited by max. junction temperature.
- 3 The power dissipation  $P_D$  is based on max. junction temperature, using junction-to-case thermal resistance.



## **Typical Electrical and Thermal Characteristics**

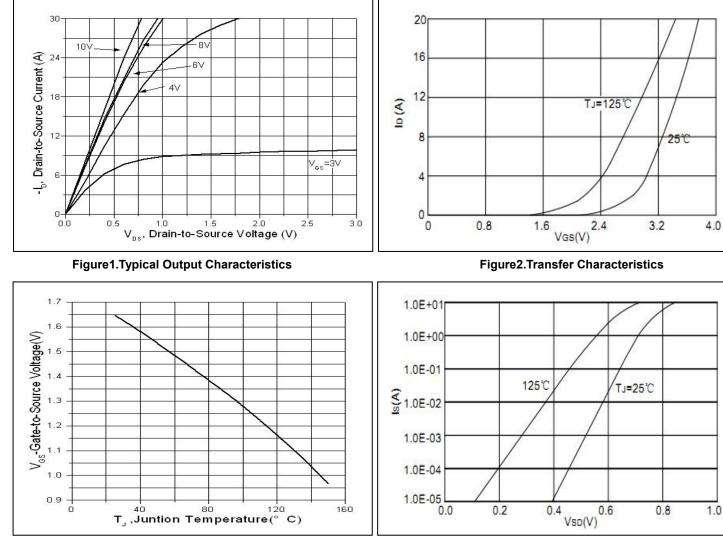


Figure3.Gate to Source Cut-off Voltage

10

8

4

2

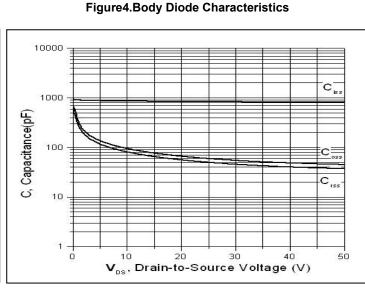
0

0

5

VGS(V)

Vos=30V Io=10A





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10

Figure5.Gate Charge

Qg(nC)

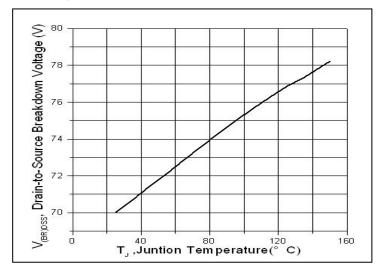
15

20

25



### **Typical Electrical and Thermal Characteristics**



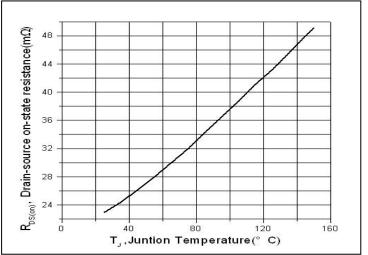


Figure7.Drain-to-Source Breakdown Voltage vs. Temperature

Figure8.Normalized On-Resistance vs. Junction Temperature

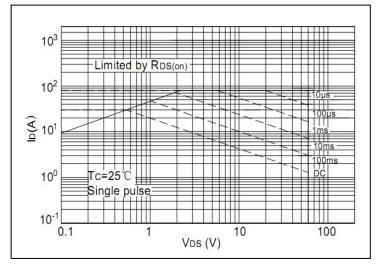


Figure9.Safe Operating Area

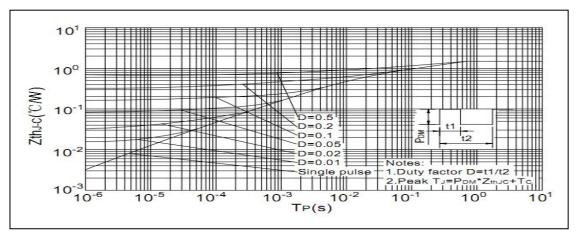
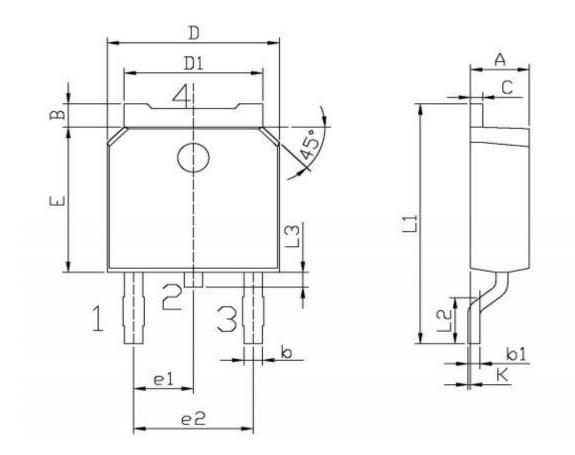


Figure10.Normalized Maximum Transient Thermal Impedance



### **Mechanical Data:**

TO-252 Package Outline (Unit : mm)



单位: mm

Symbol	Dimensions In Millimeters		Sumb a 1	Dimensions In Millimeters	
	Min	Max	Symbol	Min	Max
А	2.20	2.40	Е	5.95	6.25
В	0.95	1.25	e1	2.24	2.34
b	0.70	0.90	e2	4.43	4.73
b1	0.45	0.55	L1	9.85	10.35
С	0.45	0.55	L2	1.70	2.00
D	6. 45	6.75	L3	0.60	0.90
D1	5.10	5.50	K	0.00	0.10





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